

dbAccess European TMT Conference Technoprobe S.p.A.

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Innovation begins with us

A leading company in the field of semiconductors and microelectronics



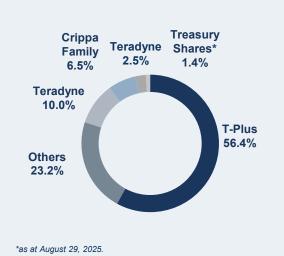
Company Overview



2024 Key financial metrics

Revenue	Ebitda	Net Income	Net Financial Position	Mkt Cap
€543.2m +22%	€136.5m 25%	€62.8m 12%	€656.3m as at	~€4,4bIn as at
CAGR 19-24	EBITDA margin	on revenues	31/12/2024	1/9/2025

Shareholding Structure





Leading player in designing and manufacturing of **probe cards**



Manufacturing process vertical integrated



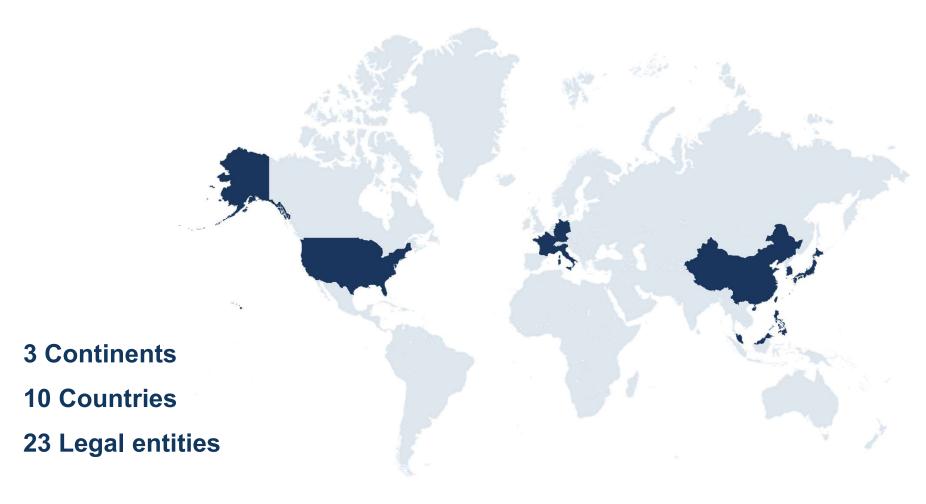
Strong focus on innovation



Extensive global presence and widespread local footprint

Where we are





What we do



Technoprobe operates both at wafer-level and in final testing



Probe Card

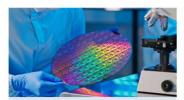
Electrical Wafer Sorting (EWS)

Chip is singulated

Chip is packaged

Final **Testing**

Integration into electronic devices



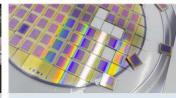
Wafer

(multi-chip)

The silicon wafer contains hundreds of unsingulated microchips



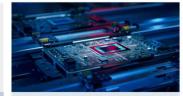
The probe card electrically tests each chip on the wafer to check functionality and identify any defects



The wafer is sliced into individual chips, known as "dies"



Each chip is encapsulated in a package that enables electrical connections and protects it from damage



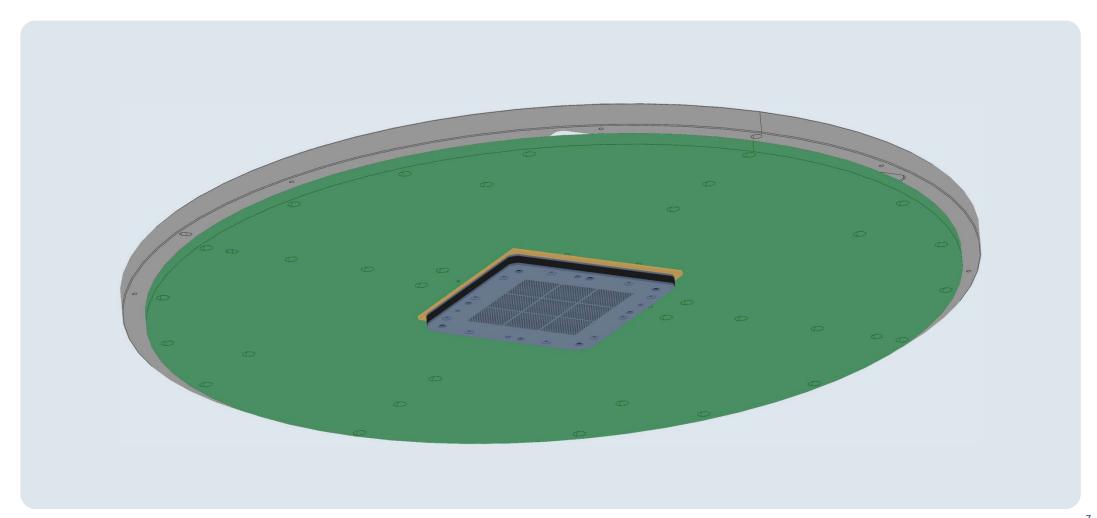
Device Interface Board

Packaged chips undergo final tests to ensure proper functionality



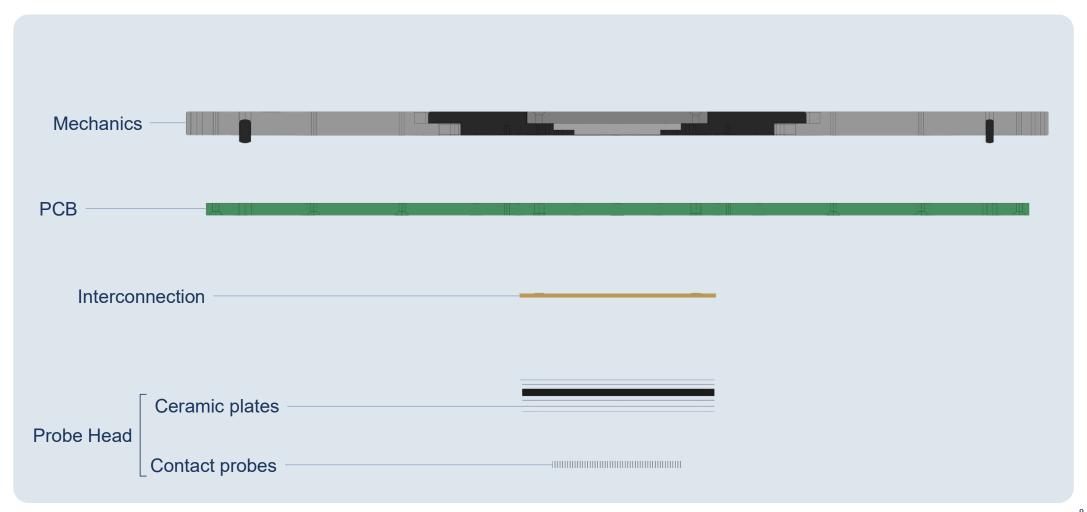
The packaged chip is integrated into electronic devices via printed circuit boards





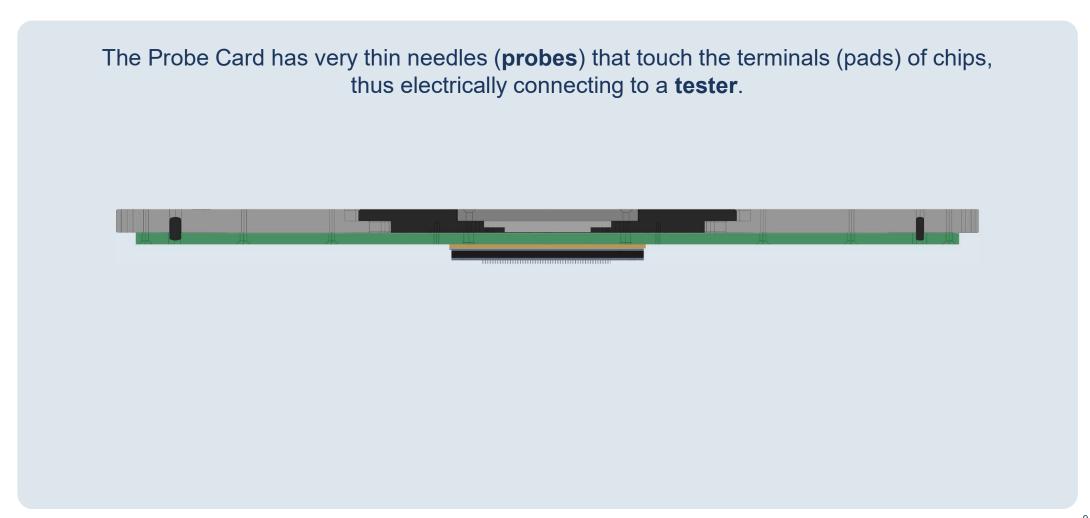
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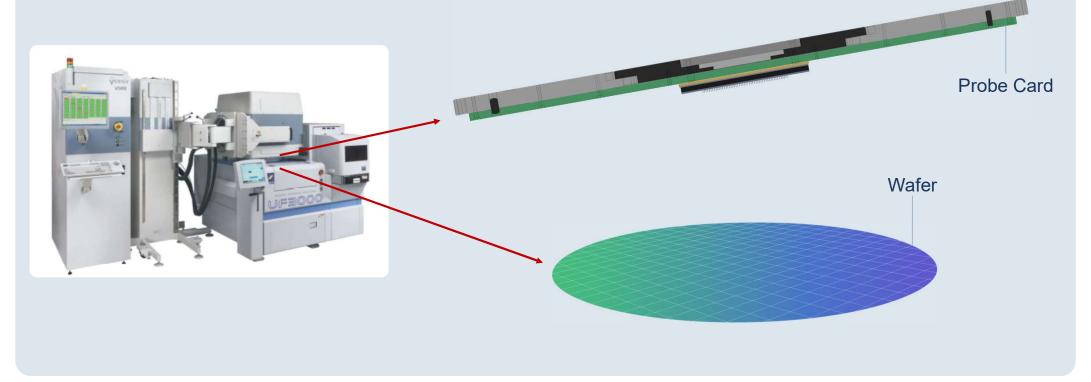
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The Probe Card has very thin needles (**probes**) that touch the terminals (pads) of chips, thus electrically connecting to a **tester**.





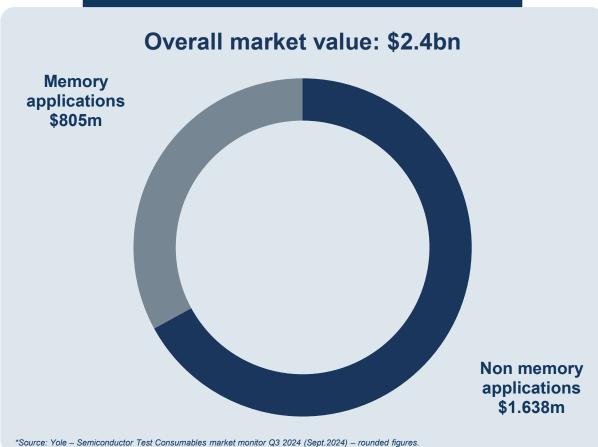
Reference Market



Overview of the Semiconductor Probe Cards market



2024 Semiconductor Probe Cards Market*



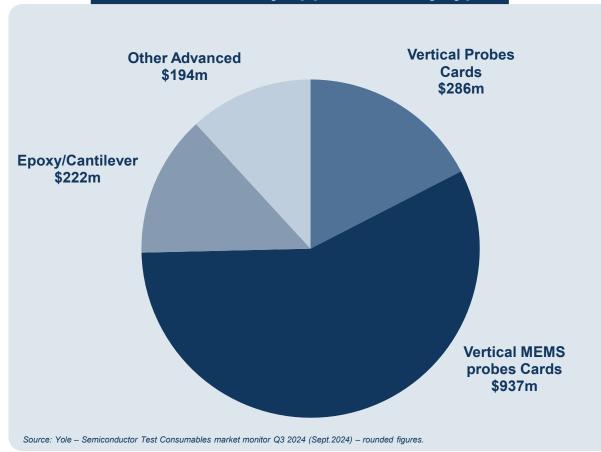
2024 Non-memory applications market share



Overview of the Semiconductor Probe Cards market



2024 Non-Memory applications by type*



2024 Vertical MEMS Probe Cards market share



Probe Cards in the semiconductor manufacturing process



FRONT END

Wafer fabrication & pre-assembly preparation

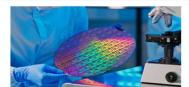
Wafer Testing Level

Wafer dicing

BACK END

Assembly & Packaging

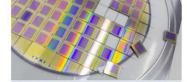
Final Testing Level



Construction of the integrated circuits (dies) that compose the wafer.



Wafer's dies testing for functional defects through probe cards. Technoprobe focuses on Vertical MEMS.



Wafer separation into individual dies, ready for subsequent assembly.



Individual die enclosure in a protective package ready for final testing and shipment.



Chip final testing with burn-in or test sockets. Technoprobe focuses on Pogo Pin for test sockets.

TPEG™ Vertical MEMS

Most advanced probe cards with applications in a wide range of end-markets



Cantilever

Less advanced type of probe card with some special end-markets applications

<1%*

Motherboard & final test board

- Motherboard used to test probe cards for tester platforms
- Pogo pins are the most value-added component for test sockets

<1%*





FRONT END		BACK END		
Wafer fabrication & pre-assembly preparation	Wafer Testing Level	Wafer dicing	Assembly & Packaging	Final Testing Level
	Wafer Level			Socket
	Singulated Die			System Level Testing
	Advanced Packaging			
				Device Interface Board
	Probe Card			

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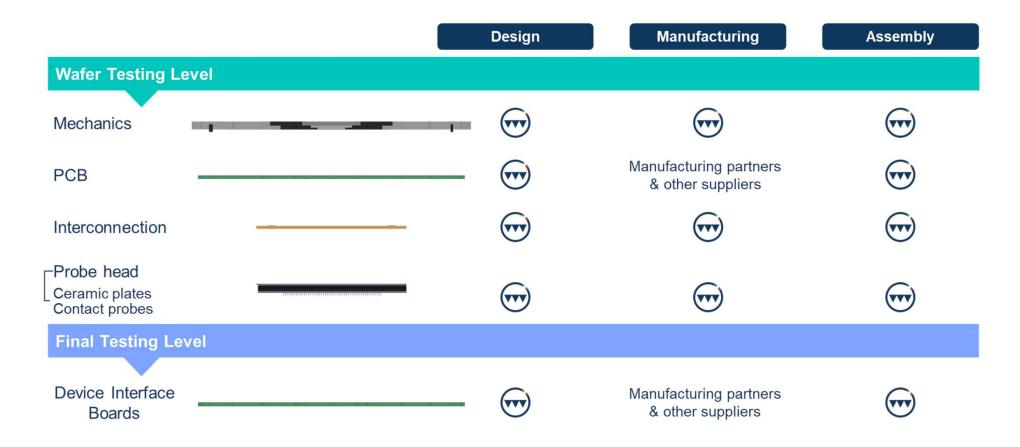


Business Model





A successful and vertically integrated business model



Built an open eco-system partnerships



TERADYNE

Accelerate growth of complete Probe Card and Final Test Interfaces by acquisition of DIS

Joint Development Projects to deliver superior customer value in SOC and Memory



ADVANTEST

Priority suppliers of PCB

Joint Development Projects to share knowledge





Probe unit

Production of probes leveraging a highly innovative and proprietary technology on **Ceramic Plates** of the **Probe Heads**

Probe head unit

Production of the **Ceramic Plates** on which Probes are then assembled

Assembly of Ceramic Plates with the probes produced in the Probe Unit

Printed Circuit Board (PCB)

Partially outsourced

Board unit

Welding and connection of the Multi Layer Organic (MLO) to the Printed Circuit Board (PCB)

Subsequently, connection of Board component (MLO and PCB welded together), with the Probe Head

Certificate unit

Final quality testing of the mechanical and electrical features of assembled probe card

Substrate Unit

Multi Layer Organic (MLO)

Mechanical Shop

- Production of the mechanical elements used across all stages of the probe card manufacturing process
- The unit is also engaged in the production of highly innovative and customized machines, not available on the market, used in the production process

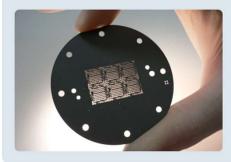
A wide range of highly innovative technologies



Advanced micromachining

Advanced laser cutting: high accuracy and fast lead time





Thin film

Strong investment in advanced thin film technology to reduce lead time and improve quality and complexity





3D MEMS

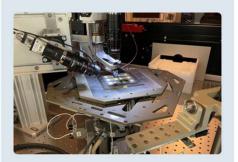
Acquisition of MICROFABRICA in 2019; the sole company in the world specialized in 3D metallic MEMS manufacturing





Advanced manufacturing

Advanced manufacturing for high volume and best quality assembly of micro components







Vision & Strategy



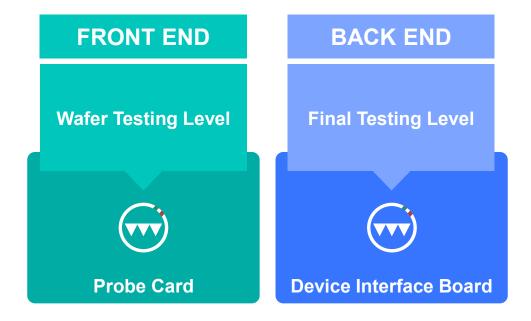
Challenges & strategic setting



1	Evolution of chip technology (more than Moore) Scaling slow down as enabler for chiplets, 3D architectures and new materials	 → Continuous investments in R&D → M&A as accelerator of technological development
2	Increase in complexity Design and manufacturing are becoming essential capabilities to reliably deliver complex solutions	 → Strategic partnerships → Vertical integration of the most value- added components of the probe card
3	Client satisfaction Reliability of the product & on-time delivery	→ Support on site → Commercial agreements

What's next?





What's next?



Consolidate the leading positioning in all test segments

FRONT END

Drive advancements in Logic Semiconductor Testing

Proliferate high-speed, high-voltage, radio frequency and silicon photonics

Enter the High Bandwidth Memory (HBM) segment

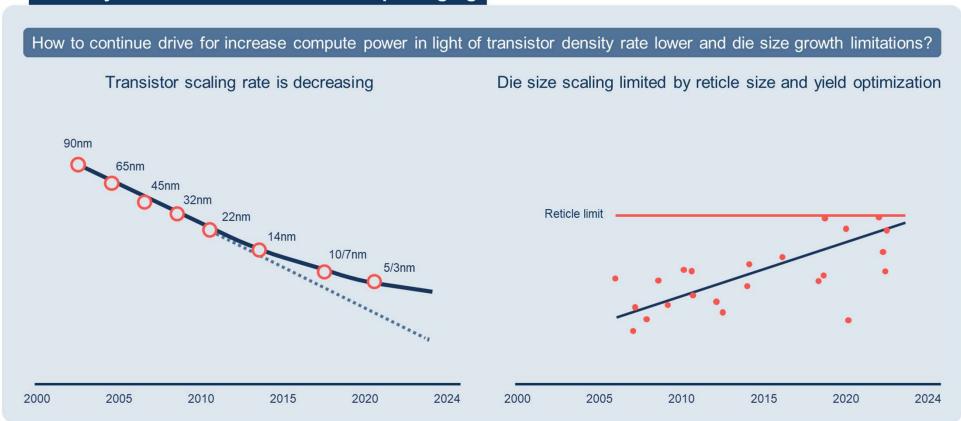
BACK END

Strengthen positioning in Final Testing





Industry motivation behind advanced packaging



FRONT END Drive advancements in Logic Semiconductor Testing

Semiconductor technology trends

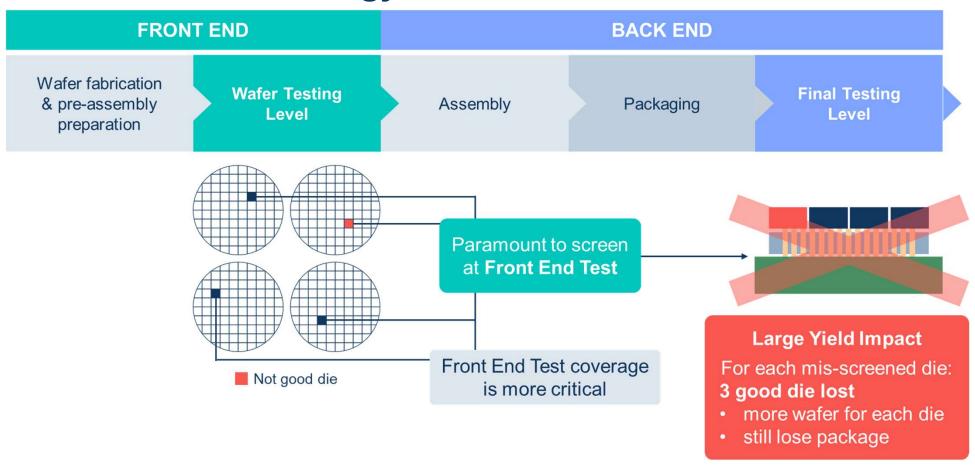


Solution: die disaggregation and advanced packaging



- Improved wafer-level yield with smaller chiplet
- Optimizing performance with mixed functionality capabilities
 - Memory
 - · Co-packaged optics
- Allows for mixed technology node application and IP reuse

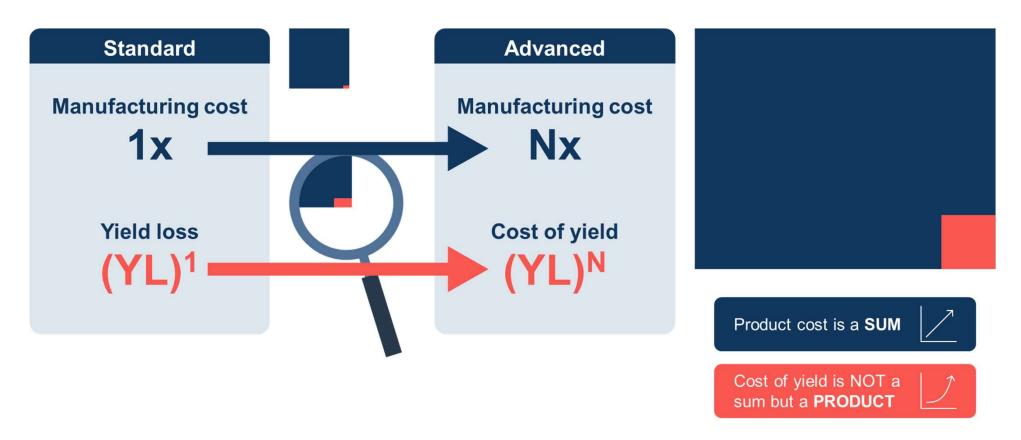
Semiconductor technology trends



FRONT END Drive advancements in Logic Semiconductor Testing

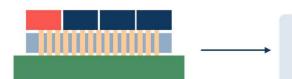
Advanced packaging versus standard





Advanced packaging versus standard





Front End Test coverage is more critical

True **Known Good Die** required!

SOLUTION

more test at probe

more Probe Cards







Fine pitch and ultra-large pin count

Necessary to effectively probe HPC and HBM's and all leading-edge product

High-speed

Short, ultra short and RF-specific needles technology to manage high speed interconnect IO, including SiPh

High power and thermal

Delivering high power to DUT in effective and reliable way

Ability to remove heat dissipated by the probe card (directly or because of power transferred from DUT to PC)

High-density interconnect

Ultra-high complexity PCB and MLO/MLC for resource fan-out on ATE/SLT

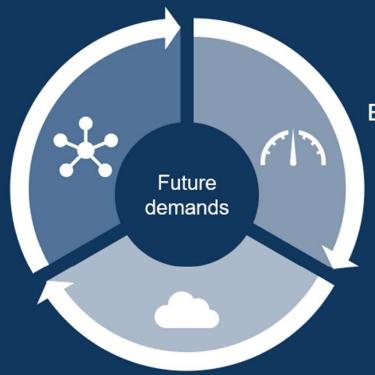
FRONT END Drive advancements in Logic Semiconductor Testing

A hungry world of wideband applications



Future demands on the network will be driven by a combination of factors:

Exponential increase in number & type of connected things



Bandwidth-hungry applications

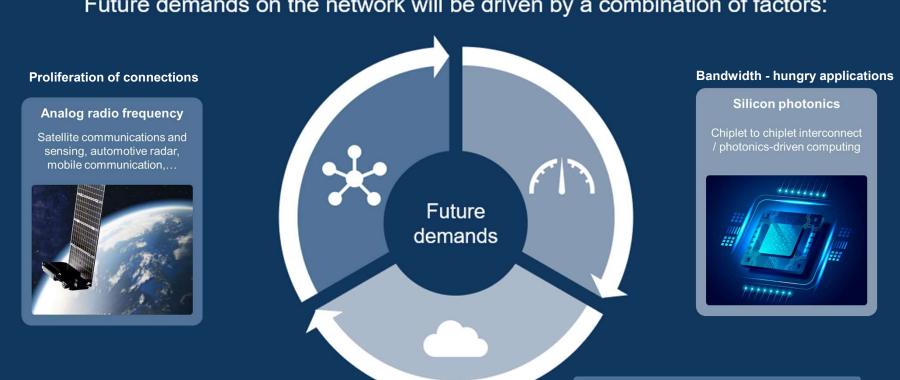
Increasing reliance on the cloud

FRONT END Proliferate high-speed, high-voltage, radio frequency and silicon photonics





Future demands on the network will be driven by a combination of factors:



FRONT END Proliferate high-speed, high-voltage, radio frequency and silicon photonics

INNOVATION BEGINS WITH US

Increasing reliance on the cloud

Chiplet probing High density and high-speed IO inside chiplet

demand for high-performance probe needles



A hungry world of wideband applications

Future demands on the network will be driven by a combination of factors:

Silicon photonics

Technoprobe technologies integrated in the same product enable...

Fine pitch probing

→ alignment with advanced packaging roadmap

Radio frequency probes

→ high-speed performances in same probe card solutions

Technoprobe IP

→ usage of standard wafer prober

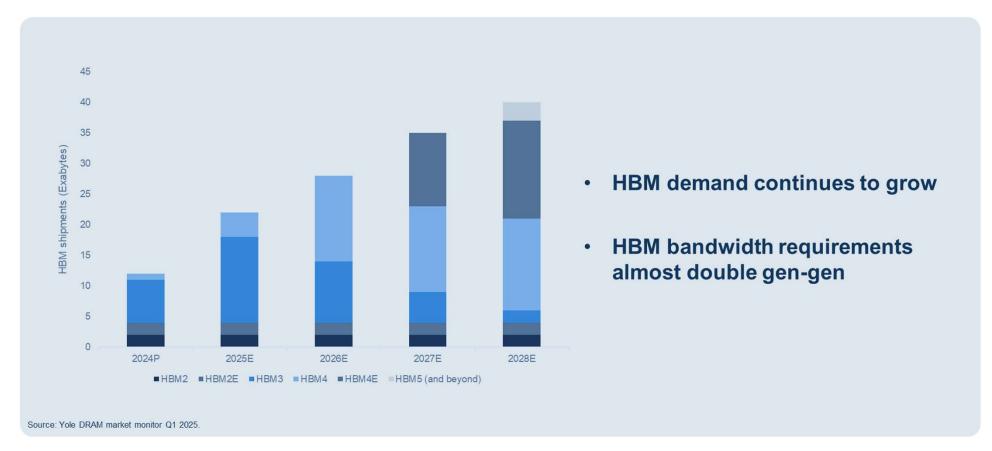
Integration of other IP from specific segment suppliers

→ flexibility and compliancy with customer preferred test method

FRONT END Proliferate high-speed, high-voltage, radio frequency and silicon photonics



DRAM & HBM: complexity as driver to new products



FRONT END Enter the High Bandwidth Memory (HBM) segment

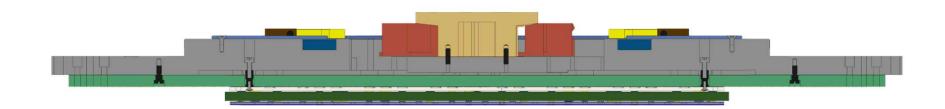




DRAM and HBM are typically tested with **microcantilever** probing technologies.

Most **advanced HBM** and Next Generation products are becoming more challenging in terms of pad pitch, signal integrity, and power.

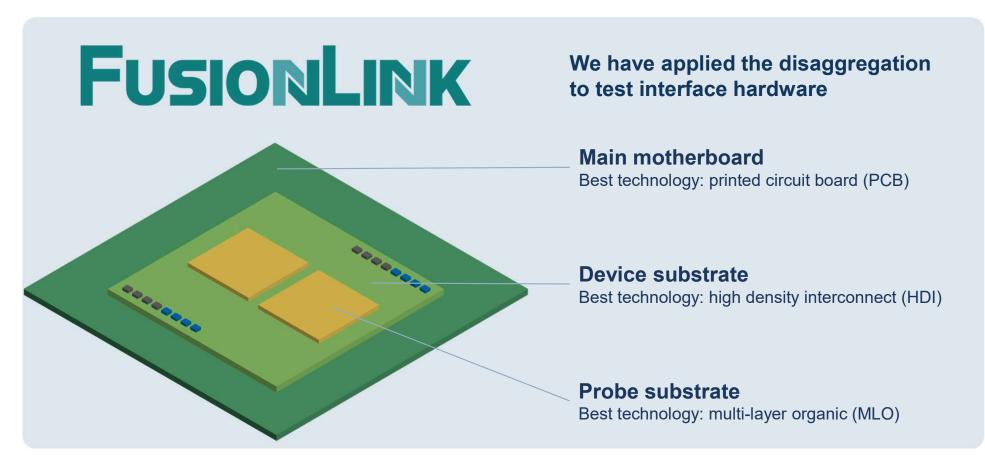
For both applications
Technoprobe is leveraging
on **Vertical MEMS** solution
and on a unique PC
architecture.



FRONT END Enter the High Bandwidth Memory (HBM) segment

FusionLink





BACK END Strengthen positioning in Final Testing







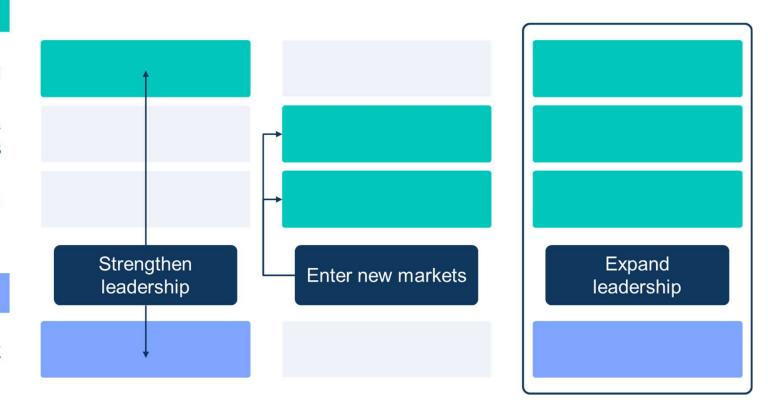
Advanced Packaging

Radio frequency & silicon photonics

HBM

BACK END

FusionLink





Financial Outlook



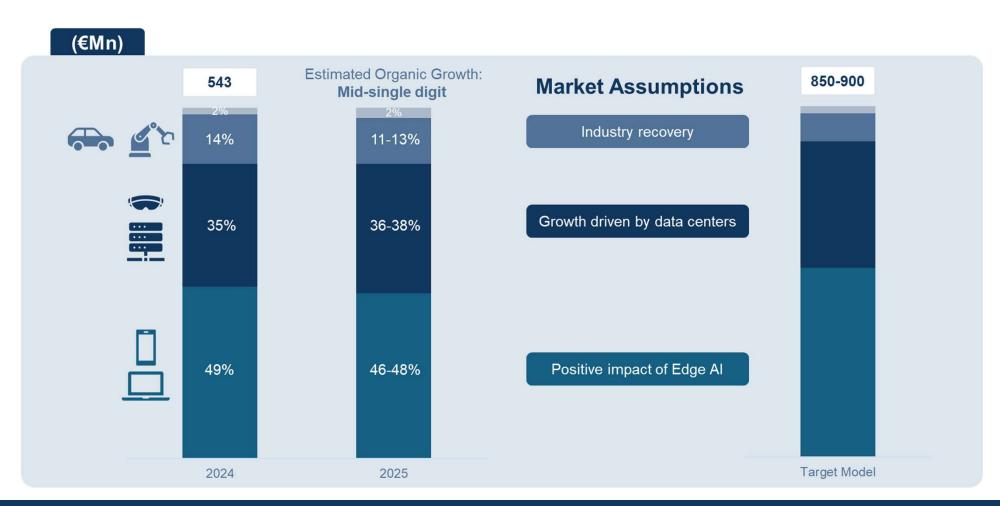
Mid-terms scenario



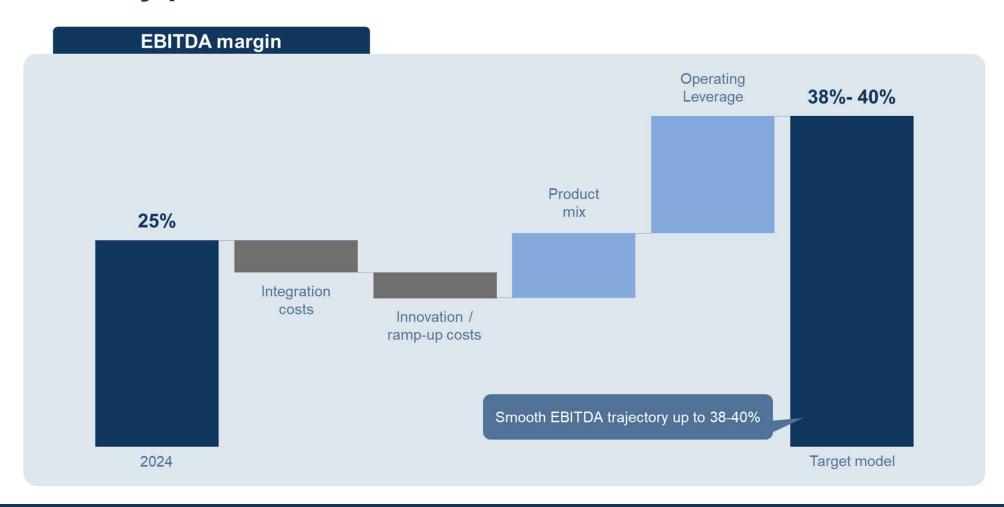
1	Technological complexity evolution	 → Testing solution for Advanced Packaging → Increase in demand for high-precision tests
2	Market trends	 → Al will lead the growth for many market segments → Expansion of memory semiconductor segments
3	Geo-political instability	 → Technological sovereignty → Commercial policies

Market trends & revenues path



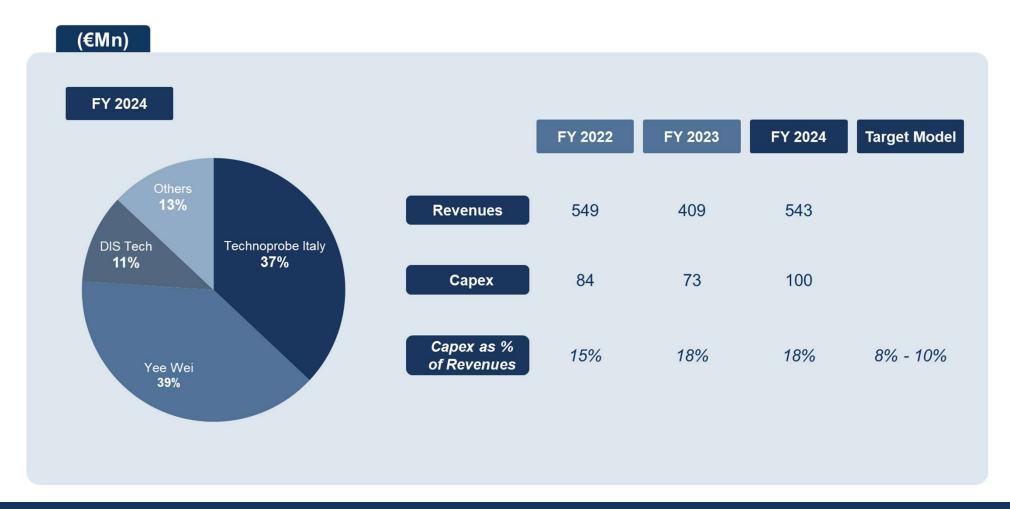


Profitability profile





Capex





H1 2025 Results



H1 2025 Market Drivers



Revenues at 325.9€m

up 7.3% QoQ up 35.2% YoY



Financial Highlights



Q2 2025

H1 2025

Revenues were 168.7€m

up 21.1% YoY, up 7.3% QoQ

Gross Profit was 79.9€m

up 38.4% YoY, with a margin of 47.3%

Ebitda was 58.3€m

up 61.8% YoY, with a margin of 34.6%

Revenues were 325.9€m

up 35.2% YoY

Gross Profit was 150.6€m

up 49.5% YoY, with a margin of 46.2%

Ebitda was 106.4€m

up 75.2% YoY, with a margin of 32.6%



Financial Highlights

	YoY Variance	Comments	
		Benefit from:	
241.1	+35.2%	 Organic growth: rising trend in AI and slight increase in consumer, partially offset by shrinkage in auto and industrial Change of perimeter (6 months of DIS revenue in H1'25 vs 1 month in H1'24) 	
100.8	+49.5%	Gross profit margin benefitted from:	
	1010/0	Recovered production efficiency	
41.8%		 Operating leverage effect 	
60.7	+75.2%	• Ebitda margin, in addition to the above,	
25.2%		benefitted also from US reorganization positive impact	
31.12.2024		 Net financial position: variance mainly attributable to solid cash flow from operating activities (+69€m), offset by capex (-28€m), 	
656.3		the acquisition of a minority stake in Yee Wei Inc. (-20€m) and Innostar Service Inc. (-7€m), together with the unrealized fx impact on foreign currency bank accounts (-29€m).	
	100.8 41.8% 60.7 25.2%	241.1 +35.2% 100.8 +49.5% 41.8% 60.7 +75.2% 25.2%	

Q3 2025 Guidance



Revenues: 137€m

(+/-3%)

Gross Margin: 41.2%

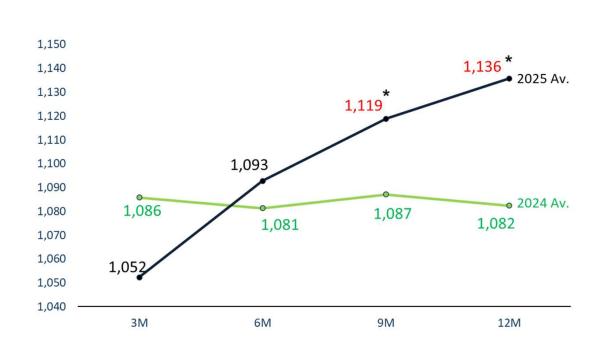
(+/-2%)

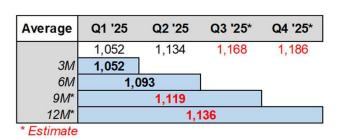
Ebitda Margin: 28.2%

(+/-2%)









Average	Q1 '24	Q2 '24	Q3 '24	Q4 '24
	1,086	1,077	1,098	1,068
3M	1,086			
6M	1,081			
9M	1,087			
12M	1,082			